



MICROCHIP

**QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY**

PCN #: KSRA-04UHXG411

**Date
October 08, 2018**

**Qualification of MTAI as a new assembly site for selected
Micrel products available in 32L VQFN (5x5x0.9mm)
package. The selected products available 24L VQFN
(4x4x0.9mm) packages will qualify by similarity (QBS).**



MICROCHIP **PACKAGE QUALIFICATION REPORT**

| | |
|----------------------------|--|
| Purpose | Qualification of MTAI as a new assembly site for selected Micrel products available in 32L VQFN (5x5x0.9mm) package. The selected products available 24L VQFN (4x4x0.9mm) packages will qualify by similarity (QBS). |
| CCB No. | 3459 and 3459.001 |
| CN | ES226534 |
| QUAL ID | Q18150 |
| MP CODE | XKAA1TPFAA04 |
| Part No. | KSZ8081RNBIA-TR |
| Bonding No. | BDM-001909 REV.A |
| <u>Package</u> | |
| Type | 32L VQFN |
| Package size | 5 x 5 x 1.0 mm |
| Die thickness | 8 mils |
| Die size | 57.8 x 37.4 mils |
| <u>Lead Frame</u> | |
| Paddle size | 150 x 150 mils |
| Material | C194 |
| Surface | Ag spot |
| Process | Etched |
| Lead Lock | No |
| Part Number | 10103204 |
| Treatment | Roughened |
| <u>Material</u> | |
| Epoxy | 3280 |
| Wire | Au wire |
| Mold Compound | G700LTD |
| Plating Composition | Matte Tin |



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information

| Assembly Lot No. | Wafer Lot No. | Date Code |
|-------------------|------------------|-----------|
| MTAI192002027.000 | DU0291033565.000 | 1833GGQ |
| MTAI192002287.000 | DU0291033565.000 | 1833HDB |
| MTAI19200288.000 | DU0291033565.000 | 1833HDC |

Result

Pass Fail _____

32L VQFN (5x5x1.0 mm) assembled by MTAI pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 2 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

| Test Number (Reference) | Test Condition | Standard/ Method | Qty. (Acc.) | Def/SS | Result | Remarks |
|---|---|----------------------|--|--|--------------------------------------|---|
| Moisture/Reflow Sensitivity Classification Test (At MSL Level 2) | 85°C/ 60%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020E) | IPC/JEDEC J-STD-020E | 135 | 0/135 | Pass | |
| Precondition Prior Perform Reliability Tests (At MSL Level 2) | Electrical Test :+25°C and 85°C System: LTX_D1X Bake 150°C, 24 hrs System: CHINEE 85°C/60%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 Electrical Test :+25°C and 85°C System: LTX_D1X | JESD22-A113 | 693(0) | 693 693 693 0/693 | Pass | Good Devices |
| Temp Cycle | Stress Condition: -65°C to +150°C, 500 Cycles System : TABAI ESPEC TSA-70H Electrical Test: + 85°C System: LTX_D1X Bond Strength: Wire Pull (> 2.5 grams) Bond Shear (>15.00 grams) | JESD22-A104 | 231(0) 15 (0) 15 (0) | 231 0/231 0/15 0/15 | Pass Pass Pass | Parts had been pre-conditioned at 260°C 77 units / lot |
| UNBIASED-HAST | Stress Condition: +130°C/85%RH, 96 hrs. Electrical Test: +25°C System: LTX_D1X | JESD22-A118 | | 231 0/231 | | Parts had been pre-conditioned at 260°C 77 units / lot |
| HAST | Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 3.3 Volts System: HAST 6000X Electrical Test: +25°C and 85°C System: LTX_D1X | JESD22-A110 | 231(0) | 231 0/231 | Pass | Parts had been pre-conditioned at 260°C 77 units / lot |

PACKAGE QUALIFICATION REPORT

| Test Number (Reference) | Test Condition | Standard/ Method | Qty. (Acc.) | Def/SS. | Result | Remarks |
|--|---|---------------------|-----------------|---------|--------|----------|
| High Temperature Storage Life | Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB | JESD22- A103 | | 45 | | 45 units |
| | Electrical Test :+25°C and 85°C System: LTX_D1X | | 45(0) | 0/45 | Pass | |
| Bond Strength Data Assembly | Wire Pull (> 2.5 grams) | M2011 | 30 (0) Wires | 0/30 | Pass | |
| | Bond Shear (>15.00 grams) | JESD22- B116 | 30 (0) bonds | 0/30 | Pass | |